10/14/2015

RELIABILITY MONITOR REPORT
FOR

X3 0.6µm Silicon Gate (C6)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1058BETM	MAX6959AAEE	MAX6959AAEE

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 9302 QUANTITY: 48 FAILS: 0 FITS: 12.3

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2014 and 9/30/2015 .

Process Information:

Process Description: X3 0.6µm Silicon Gate (C6)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1420	MAX6959AAEE+	135°C	1000	HRS	48	0	SL10EA083AG
					Total:		**0**	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1412	MAX1058BETM+	150°C	1000	HRS	80	0	SEQ0LU041AG
STORAGE LIFE	1420	MAX6959AAEE+	150°C	1000	HRS	80	0	SL10EA083AG
					Total:		**0**	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1412	MAX1058BETM+	-65C TO +150C (Condition C)	500	CYS	80	0	SEQ0LU041AG
TEMP CYCLE, 5' RAMP, 10' DWELL	1420	MAX6959AAEE+	-65C TO +150C (Condition C)	500	CYS	65	0	SL10EA083AG
					Total:		**0**	

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